



# CERTIFICATE OF ACCREDITATION

## ANSI-ASQ National Accreditation Board

500 Montgomery Street, Suite 625, Alexandria, VA 22314, 877-344-3044

This is to certify that

**Antibus Scales & Systems, Inc.**

**4310 Technology Drive**

**South Bend, IN 46628**

has been assessed by ANAB  
and meets the requirements of international standard

**ISO/IEC 17025:2005**

and national standard

**ANSI/NCSL Z540-1-1994 (R2002)**

while demonstrating technical competence in the field of

**CALIBRATION**

Refer to the accompanying Scope of Accreditation for information regarding the types of calibrations to which this accreditation applies.

L2253.01

Certificate Number

  
ANAB Approval

Certificate Valid: 10/11/2017-05/11/2020  
Version No. 002 Issued: 10/11/2017



This laboratory is accredited in accordance with the recognized International Standard ISO/IEC 17025:2005. This accreditation demonstrates technical competence for a defined scope and the operation of a laboratory quality management system (refer to joint ISO-ILAC-IAF Communiqué dated April 2017).



**SCOPE OF ACCREDITATION TO ISO/IEC 17025:2005 AND  
ANSI/NCSL Z540-1-1994 (R2002)**

**Antibus Scales & Systems, Inc.**

4310 Technology Drive  
South Bend, IN 46628  
Henry Meyers  
574-233-3160

**CALIBRATION**

Valid to: **May 11, 2020**

Certificate Number: **L2253.01**

**Electrical – DC/Low Frequency**

Parameter / Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method and/or Equipment
DC Current Measure and Source	4 mA 10 mA 20 mA	0.004 mA 0.005 mA 0.006 mA	Fluke 740 Series Process Calibrator
AC Source Current	(0.33 to 3.3) mA (10 to 20) Hz (20 to 45) Hz 45 Hz to 1KHz (1 to 5) kHz (5 to 10 kHz (10 to 30) kHz	0.15 mA/A + 0.15 µA 1 mA/A + 0.15 µA 76 mA/A + 0.15 µA 57 mA/A + 0.2 µA 63 mA/A + 0.3 µA 56 mA/A + 0.6 µA	Fluke 5520A
AC Source	(3.3 to 33) mA (10 to 20) Hz (20 to 45) Hz 45 Hz to 1KHz (1 to 5) kHz (5 to 10 kHz (10 to 30) kHz	2 mA/A + 2 µA 0.9 mA/A + 2 µA 1.4 mA/A + 2 µA 0.74 mA/A + 2 µA 2 mA/A + 3 µA 3 mA/A + 4 µA	Fluke 5520A
	(33 to 330) mA (10 to 20) Hz (20 to 45) Hz 45 Hz to 1KHz (1 to 5) kHz (5 to 10 kHz (10 to 30) kHz	1.4 mA/A + 20 µA 0.7 mA/A + 20 µA 0.44 mA/A + 20 µA 178 mA/A + 50 µA 2 mA/A + 100 µA 3 mA/A + 200 µA	

**Electrical – DC/Low Frequency**

Parameter / Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method and/or Equipment
AC Source	(0.33 to 1.1) A (10 to 20) Hz (20 to 45) Hz 45 Hz to 1KHz (1 to 5) kHz (5 to 10 kHz)	1.4 mA/A + 100 $\mu$ A 1.4 mA/A + 100 $\mu$ A 0.4 mA/A + 100 $\mu$ A 4.6 mA/A + 1 mA 19 mA/A + 5 mA	Fluke 5520A
	(1.1 to 3) A (10 to 20) Hz 45 Hz to 1KHz (1 to 5) kHz (5 to 10 kHz)	8 mA/A + 100 $\mu$ A 0.54 mA/A + 100 $\mu$ A 4.6 mA/A + 1 mA 19 mA/A + 5 mA	
	(3 to 11) A (45 to 100) Hz 100 Hz to 1 kHz (1 to 5) kHz)	0.54 mA/A + 2 mA 0.81 mA/A + 2 mA 23 mA/A + 2 mA	
Resistance Source	(0 to 11) $\Omega$ (11 to 33) $\Omega$ (33 to 110) $\Omega$ (110 to 330) $\Omega$ 330 to 1.1k $\Omega$ (1.1 to 3.3) k $\Omega$ (3.3 to 11) k $\Omega$ (11 to 33) k $\Omega$ (33 to 110) k $\Omega$ (110 to 330) k $\Omega$ 330 to 1.1 M $\Omega$ (1.1 to 3.3) M $\Omega$ (3.3 to 11) M $\Omega$ (11 to 33) M $\Omega$ (33 to 110) M $\Omega$	178 $\mu\Omega/\Omega$ + 5 $\mu\Omega$ 24 $\mu\Omega/\Omega$ + 7.5 $\mu\Omega$ 23 $\mu\Omega/\Omega$ + 7 $\mu\Omega$ 22 $\mu\Omega/\Omega$ + 10 $\mu\Omega$ 22 $\mu\Omega/\Omega$ + 10 $\mu\Omega$ 22 $\mu\Omega/\Omega$ + 100 $\mu\Omega$ 22 $\mu\Omega/\Omega$ + 100 $\mu\Omega$ 22 $\mu\Omega/\Omega$ + 1 m $\Omega$ 22 $\mu\Omega/\Omega$ + 1 m $\Omega$ 26 $\mu\Omega/\Omega$ + 0.01 $\Omega$ 28 $\mu\Omega/\Omega$ + 0.01 $\Omega$ 63 $\mu\Omega/\Omega$ + 0.15 $\Omega$ 100 $\mu\Omega/\Omega$ + 0.25 $\Omega$ 203 $\mu\Omega/\Omega$ + 12.5 $\Omega$ 415 $\mu\Omega/\Omega$ + 15 $\Omega$	Fluke 5520A
Resistance Measure	55 $\Omega$ 250 $\Omega$ 680 $\Omega$	0.087 $\Omega$ 0.14 $\Omega$ 0.33 $\Omega$	Fluke 740 Series Process Calibrator
Electrical Simulation of RTD Indicating Devices Pt 385 100 $\Omega$	(-180 to 750) $^{\circ}$ C	0.62 $^{\circ}$ C	Fluke 740 Series Process Calibrator



Electrical – DC/Low Frequency

Parameter / Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method and/or Equipment
DC Voltage Source	(0 to 330) mV (0 to 3.3) V (0 to 33) V (33 to 330) V (100 to 1 000) V	17 $\mu$ V/V + 1 $\mu$ V 9.4 $\mu$ V/V + 2 $\mu$ V 10 $\mu$ V/V + 20 $\mu$ V 15 $\mu$ V/V + 150 $\mu$ V 14.99 $\mu$ V/V + 1.5 mV	Fluke 5520A
AC Voltage Source	(1 to 33) mV (10 to 45) Hz 45 Hz to 10 kHz (10 to 20) kHz (20 to 50) kHz (50 to 100) kHz (100 to 500) kHz (33 to 330) mV (10 to 45) Hz 45 Hz to 10 kHz (10 to 20) kHz (20 to 50) kHz (50 to 100) kHz (100 to 500) kHz (0.33 to 3.3) V (10 to 45) Hz 45 Hz to 10 kHz (10 to 20) kHz (20 to 50) kHz (50 to 100) kHz (100 to 500) kHz (3.3 to 33) V (10 to 45) Hz 45 Hz to 10 kHz (10 to 20) kHz (20 to 50) kHz (50 to 100) kHz (33 to 330) V (10 to 45) Hz 45 Hz to 10 kHz (10 to 20) kHz (20 to 50) kHz (50 to 100) kHz	623 $\mu$ V/V + 6 $\mu$ V 170 $\mu$ V/V + 6 $\mu$ V 198 $\mu$ V/V + 6 $\mu$ V 813 $\mu$ V/V + 6 $\mu$ V 2.7 mV/V + 12 $\mu$ V 6 mV/V + 12 $\mu$ V 242 $\mu$ V/V + 8 $\mu$ V 136 $\mu$ V/V + 8 $\mu$ V 132 $\mu$ V/V + 8 $\mu$ V 280 $\mu$ V/V + 8 $\mu$ V 625 $\mu$ V/V + 32 $\mu$ V 1.6 mV/V + 70 $\mu$ V 243 $\mu$ V/V + 50 $\mu$ V 136 $\mu$ V/V + 60 $\mu$ V 162 $\mu$ V/V + 60 $\mu$ V 244 $\mu$ V/V + 50 $\mu$ V 538 $\mu$ V/V + 125 $\mu$ V 2 mV/V + 600 $\mu$ V 240 $\mu$ V/V + 650 $\mu$ V 120 $\mu$ V/V + 600 $\mu$ V 187 $\mu$ V/V + 600 $\mu$ V 281 $\mu$ V/V + 600 $\mu$ V 696 $\mu$ V/V + 1.6 mV 166 $\mu$ V/V + 2 mV 162 $\mu$ V/V + 6 mV 192 $\mu$ V/V + 6 mV 245 $\mu$ V/V + 6 mV 2 mV/V + 50 mV	Fluke 5520A



**Electrical – DC/Low Frequency**

Parameter / Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method and/or Equipment
AC Voltage Source	(330 to 1 020) V 45 Hz to 1 kHz (1 to 5) kHz (5 to 10) kHz	237 $\mu\text{V}/\text{V} + 10 \text{ mV}$ 199 $\mu\text{V}/\text{V} + 10 \text{ mV}$ 238 $\mu\text{V}/\text{V} + 10 \text{ mV}$	Fluke 5520A
Electrical Simulation of Thermocouple Indicating Devices	Type K (-200 to 1 300) °C Type J (-210 to 1 200) °C Type T (-250 to 400) °C	0.69 °C 0.64 °C 0.78 °C	Fluke 740 Series Process Calibrator

**Length – Dimensional Metrology**

Parameter / Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method and/or Equipment
End Standards	(Up to 12) in	36 $\mu\text{in}$	Gage Blocks and P & W LMU 175
Rules and Scales	(0 to 72) in	0.013 in	Gage Blocks and magnifier
Plug / Pin Gages	Up to 4 in	28 $\mu\text{in}$	P&W LMU 175 and Gage Blocks
Thread Wires (80 to 6) TPI	(0.007 to 0.097) in	19 $\mu\text{in}$	P&W LMU 175 and Gage Blocks
Gage Blocks	(0 to 4) in	6.1 $\mu\text{in}$	Comparator and Gage Blocks
Torque Arms	(0 to 10) in	589 $\mu\text{in}$	Surface Plate and Height Gage
OD Cylinder Gages	(0 to 1) in (1 to 10) in	(10 + 1.5L) $\mu\text{in}$ (11 + 6L) $\mu\text{in}$	P&W LMU 175 and Gage Blocks
ID Cylinder Gages	(0.04 to 1) in (1 to 12) in	(10 + 1.5L) $\mu\text{in}$ (11 + 6L) $\mu\text{in}$	
Thread Plugs Pitch Diameter (80 to 6) TPI Major Diameter	(0.007 to 0.097) in Up to 4 in	(121 + 0.12L) $\mu\text{in}$ (42 + 0.33L) $\mu\text{in}$	P&W LMU 175 Gage Blocks Thread Wires
Root Radius & Minor Diameter	(0.06 to 4) in	(216 + 0.05L) $\mu\text{in}$	Optical Comparator



Length – Dimensional Metrology

Parameter / Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method and/or Equipment
Almen Kit Step Blocks Depth Flatness	(0.005 to 0.025) in (0.2 to 0.6) mm (0 to 2) inD	40 $\mu$ m 1 $\mu$ m 0.05 $\mu$ m	Gage Blocks and Electronic Indicator Optical Flat
Height Gages 0.000 1 in resolution 0.001 in resolution	(0 to 24) in	(57.3 + 0.6L) $\mu$ m (577 + 0.07L) $\mu$ m	Gage Blocks
Indicators 0.000 05 in resolution 0.000 1 in resolution 0.000 5 in resolution 0.001 in resolution	(0 to 6) in	(29 + 0.28L) $\mu$ m (58 + 0.14L) $\mu$ m (289 + 0.04L) $\mu$ m (577 + 0.02L) $\mu$ m	Gage Blocks
Calipers 0.000 5 in resolution 0.001 in resolution	(0 to 40) in	(289 + 0.26L) $\mu$ m (577 + 0.13L) $\mu$ m	Gage Blocks
OD Micrometers 0.000 05 in resolution 0.000 1 in resolution 0.001 in resolution	(0 to 4) in (0 to 12) in (0 to 24) in	(29.1 + 0.4L) $\mu$ m (58 + 0.46L) $\mu$ m (578 + 0.1L) $\mu$ m	Gage Blocks
Bore Gages	(0.25 to 6) in	586 $\mu$ m	Master Ring and Gage Blocks
Almen Gauges Indicator Accuracy	(0.005 to 0.025) in (0.2 to 0.6) mm	80 $\mu$ m 2 $\mu$ m	Step Blocks
Depth Gages 0.000 1 in resolution 0.001 in resolution	(0 to 12) in	(289 + 0.05L) $\mu$ m (577 + 0.03L) $\mu$ m	Depth Standard/Gage Blocks
Optical Comparators Linear Travel Angle	(0 to 10) in Angle 0° to 90°	141 $\mu$ m 0.1 °	Gage Blocks/Gage Balls/Sine Bar



Mass

Parameter / Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method and/or Equipment
Force Gages (0.000 1 lbf Resolution) (0.000 2 lbf Resolution) (0.000 5 lbf Resolution) (0.01 lbf Resolution) (0.1 lbf Resolution) (0.2 lbf Resolution) (0.5 lbf Resolution)	(0 to 5) lbf (0 to 11) lbf (0 to 22) lbf (0 to 110) lbf (0 to 300) lbf (0 to 1 000) lbf (0 to 3 000) lbf	0.000 59 lbf 0.002 lbf 0.003 lbf 0.044 lbf 0.15 lbf 0.31 lbf 0.79 lbf	Class 6 Weights
Force – Tension and Compression (1 lbf resolution) (10 lbf resolution) (10 lbf resolution)	(0 to 10 000) lbf (0 to 10 000) lbf (0 to 100 000) lbf	2.3 lbf 18 lbf 60 lbf	Load Cells
ASTM D 2240, Direct Verification of Types A, D, & Durometers,  Force	(20 to 90) Duro	0.6 Duro	Balance
Indenter Extension Indenter Diameter Indenter Tip Radius	(0 to 0.2) in	190 µin	Optical Comparator
Indenter Tip Angle	(0 to 35) Deg	0.1 Deg	Optical Comparator
Indirect Verification of Rockwell Hardness Testers	HRA High Middle Low HRBW High Middle Low HRC High Middle Low HR15N High Middle Low	0.9 HRA 0.9 HRA 1.1 HRA 0.98 HRBW 1.1 HRBW 1.2 HRBW 0.95 HRC 0.97 HRC 0.97 HRC 0.89 HR15N 1.1 HR15N 1.2 HR15N	ASTM E 18 Hardness Test Blocks



Mass

Parameter / Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method and/or Equipment
Indirect Verification of Rockwell Hardness Testers	HR15TW		ASTM E 18 Hardness Test Blocks
	High	0.96 HR15TW	
	Middle	1.1 HR15TW	
	Low	0.89 HR15TW	
	HR30N		
	High	0.95 HR30N	
	Middle	0.89 HR30N	
	Low	1.1 HR30N	
	HR30TW		
	High	1.2 HR30TW	
	Middle	1.2 HR30TW	
	Low	1.2 HR30TW	
Indirect Verification of Brinell Hardness Tester	HBW 10/3 000 High		ASTM E10-14
	Diameter	0.05mm	
	Hardness	18 HBW	
	HBW 10/3 000Low		
	Diameter	0.09 mm	
	Hardness	9.2 HBW	
	HBW 10/1 500 High		
	Diameter	0.09 mm	
	Hardness	23 HBW	
	HBW 10/1 500 Low		
	Diameter	0.04mm	
	Hardness	3.5 HBW	
HBW 10/500 High			
Diameter	0.06 mm		
Hardness	6.7 HBW		
HBW 10/500 Low			
Diameter	0.06 mm		
Hardness	2.6 HBW		
Class F Mass Standards	20 lb	0.000 11 lb	Modified Substitution
	25 lb	0.000 37 lb	
	50 lb	0.000 5 lb	
	500 lb	0.011 lb	
	1 000 lb	0.015 lb	
	10 kg	0.19 g	
	20 kg	0.21 g	
	25 kg	0.21 g	





Mass

Parameter / Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method and/or Equipment
Lab Balances (0.000 1 g Resolution) (0.001 g Resolution) (0.01 g Resolution) (0.1 g Resolution)	(0 to 310) g (0 to 510) g (0 to 1 000) g (0 to 16) kg	0.7 mg 1.8 mg 16 mg 0.17 g	Class 1 Weights and NIST Handbook 44 utilized for the Calibration of Weighing Systems
Lab Balances (0.1 g Resolution)	(0 to 8 100) g	0.16 g	Class 2 Weights and NIST Handbook 44 utilized for the Calibration of Weighing Systems
High Resolution Unmarked Scales (0.000 1 kg Resolution)	(0 to 40) kg (40 to 150) kg	0.0004 kg 0.0009 kg	Class 1 and Class 2 Weights with Substitution to range of use
High Resolution Unmarked Scales <sup>3</sup> (0.000 02 lb Resolution) (0.000 05 lb Resolution) (0.000 1 lb Resolution) (0.000 2 lb Resolution) (0.000 5 lb Resolution) (0.001 lb Resolution) (0.002 lb Resolution) (0.005 lb Resolution)	(0 to 6) lb (0 to 12) lb (0 to 30) lb (0 to 70) lb (0 to 120) lb (0 to 200) lb (0 to 300) lb (0 to 600) lb	0.000 6 lb 0.001 2 lb 0.005 8 lb 0.006 9 lb 0.012 lb 0.023 lb 0.035 lb 0.07 lb	Class F Weights and NIST Handbook 44 utilized for the Calibration of Weighing Systems
Industrial and Commercial Scales <sup>4</sup> (0.01 lb Resolution) (0.02 lb Resolution) (0.05 lb Resolution) (0.1 lb Resolution) (0.2 lb Resolution) (0.5 lb Resolution) (1 lb Resolution) (2 lb Resolution) (5 lb Resolution) (10 lb Resolution) (20 lb Resolution)	(0 to 100) lb (0 to 200) lb (0 to 500) lb (0 to 1 000) lb (0 to 2 000) lb (0 to 5 000) lb (0 to 10 000) lb (0 to 20 000) lb (0 to 50 000) lb (0 to 100 000) lb (0 to 200 000) lb	0.016 lb 0.04 lb 0.1 lb 0.2 lb 0.4 lb 1 lb 2 lb 4 lb 11 lb 15 lb 35 lb	Class F Weights and NIST Handbook 44 utilized for the Calibration of Weighing Systems



**Mass**

Parameter / Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method and/or Equipment
Industrial and Commercial Scales <sup>4</sup> (0.001 kg resolution) (0.002 kg resolution) (0.005 kg resolution) (0.01 kg resolution) (0.02 kg resolution) (0.05 kg resolution) (0.1 kg resolution) (0.2 kg resolution) (0.5 kg resolution)	(0 to 10) kg (0 to 20) kg (0 to 50) kg (0 to 100) kg (0 to 200) kg (0 to 500) kg (0 to 1 000) kg (0 to 2 000) kg (0 to 5 000) kg	0.002 kg 0.004 kg 0.009 kg 0.02 kg 0.04 kg 0.1 kg 0.2 kg 0.4 kg 1 kg	Class F Weights and NIST Handbook 44 utilized for the Calibration of Weighing Systems
Torque Analyzers – Fixed Points	1 ozf·in to 50 lbf·in (25 to 250) lbf·in (100 to 1 000) lbf·in (25 to 250) lbf·ft	0.049% of reading 0.048% of reading 0.021% of reading 0.018% of reading	Torque Arm and Class 6 Weights
Torque Wrenches	(1 to 10) ozf·in	1.3 % of reading	Torque Analyzer
	(5 to 50) lbf·in (25 to 250) lbf·in (100 to 1 000) lbf·in (25 to 250) lbf·ft	2.3% of reading	
Hydraulic	(30 to 10 000) psi	0.005 % of reading	Deadweight Tester
Pneumatic <sup>1</sup>	(0 to 30) psi (30 to 10 000) psi	0.04 psi 12 psi	Pressure Transducer
Vacuum <sup>1</sup>	(-15 to 0) psi	0.04 psi	Vacuum Transducer

**Thermodynamic**

Parameter / Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method and/or Equipment
Humidity Indicators	11 % RH 33 % RH 75 % RH	0.74% RH 0.65% RH 0.94% RH	Saturated Salts & Capacitive Probe
	(20 to 90) % RH	1.6 % RH	Dwyer Comparison <sup>1</sup>



Thermodynamic

Parameter / Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method and/or Equipment
Temperature Indicators and probe systems Environmental Temperature indicators and dataloggers	(-30 to 150) °C	0.92 °C	Envirotronics Chamber Temperature Indicator
Temperature Indicators and probe systems	(35 to 375) °C	1.3 °C	Fluke 9100S Drywell
Infrared Thermometers	(35 to 100) °C (100 to 350) °C (350 to 500) °C	0.62 °C 1.5 °C 2 °C	Fluke 4181 $\lambda = (8 \text{ to } 14) \mu\text{m}$ $\epsilon = (0.9 \text{ to } 1.0)$

Calibration and Measurement Capability (CMC) is expressed in terms of the measurement parameter, measurement range, expanded uncertainty of measurement and reference standard, method, and/or equipment. The expanded uncertainty of measurement is expressed as the standard uncertainty of the measurement multiplied by a coverage factor of 2 ( $k=2$ ), corresponding to a confidence level of approximately 95%.

Notes:

1. On-site calibration service is available for this parameter, since on-site conditions are typically more variable than those in the laboratory, larger measurement uncertainties are expected on-site than what is reported on the accredited scope.
2.  $L$  = Length in inches,  $D$  = Diameter in inches
3. High Resolution Unmarked Scales include high resolution scales not complying with the accuracy class parameters of Table 3 of NIST Handbook 44.
4. Industrial Scales include but are not limited to lab balances, bench scales, floor scales, tank and hopper scales, and vehicle scales.
5. Antibus Scales & Systems, Inc has resident technicians located in Perrysburg OH.
6. This scope is formatted as part of a single document including Certificate of Accreditation No. L2253.01.



Vice President

